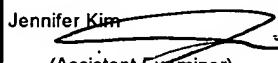
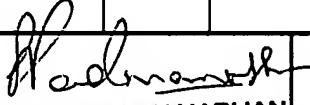


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ISSUE CLASSIFICATION							
ORIGINAL			CROSS REFERENCE(S)				
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
514	43	514	410	416			
INTERNATIONAL CLASSIFICATION							
A	6	I	K	31170			
A	6	I	K	31140			
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				/			
Jennifer Kim  (Assistant Examiner)	5/10/05 (Date)		 SREENI PADMANABHAN SUPERVISORY PATENT EXAMINER (Primary Examiner)	Total Claims Allowed: 6 Print Claim(s) 1 (Date) 5/15/05		O.G. Print Flg. 0	
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